Materials Characterization : Introduction to Microscopic and Spectroscopic Methods

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Publisher, Wiley-VCH

<http://site.ebrary.com/lib/aalto/reader.action?docID=10743902>

**Index**

The yellow marked chapters are important information about the topics included in this course. The estimated number of pages of the chapter that are relevant to the exam are (marked) and before the contact session you should study the chapter.

1. Light Microscopy (34 p.)
   1. Operating principles p. 1-8
   2. Instrumentation 9-15
   3. Specimen Preparation 15-25
   4. Imaging Modes 26-38
   5. Confocal Microscopy 39-44
2. X-Ray Diffraction Methods, XRD (27 p.)
   1. X-ray radiation 47-51
   2. Theoratical Bacground of Diffraction 52-61
   3. X-Ray Diffractometry 62-74
   4. Wide-Angle X-Ray Diffraction and Scattering 75- 81
3. Transmission Electron Microscopy TEM (23 p.)
   1. Instrumentation 83-89
   2. Specimen Preparation 90-93
   3. Image Modes 94-106
   4. Selected-Area Diffraction (SAD) 107-116
   5. Images of Crystal Defects 117-125
4. Scanning Electron Microscopy SEM (23 p.)
   1. Instrumentation 127-134
   2. Contrast formation 165-140
   3. Operation variables 141-144
   4. Specimen Preparation 145-150
   5. Electron Backscatter Diffraction (EBSD) 151-155
   6. Environmental SEM 156-159
5. Scanning Probe Microscopy (mainly AFM, 22 p.)
   1. Instrumentation 163-165
   2. Scanning Tunneling Microscopy 166-169
   3. Atomic Force Microscopy (AFM) 170-183
   4. Image Artifacts 183-188
6. X-Ray spectroscopy for Elemental Analysis [XRF 4 p., EDS 23 p.]
   1. Features of Characteristic X-rays 191-195
   2. X-Ray Fluorescence Spectrometry 196- 206 (WDS and EDS)
   3. EDS in Electron Microscopes 207-209
   4. Qualitative and Quantitative Analysis 211-219
7. Electron Spectroscopy for Surface Analysis (XPS + Auger 28 p.)
   1. Basic Principles 221-222 (XPS)

7.1.2 Auger 222

7.2 Instrumentation 225-229

7.3 Characteristics of Electron Spectra 230-234 (XPS + Auger)

7.4 Qualitative and Quantitative Analysis 235- 249

1. Secondary Ion Mass Spectrometry for Surface Analysis, SIMS (16 p.)
   1. Basic principles 253-257
   2. Instrumentation 257-263 (264-266)
   3. Surface structure analysis 266-272
   4. SIMS imaging
   5. SIMS depth profiling
2. Vibrational Spectroscopy for Molecular Analysis, Raman (~30 p.)
   1. Theoretical Background 283-297 (FTIR ones not included)
   2. FTIS 297-309
   3. Raman Microscopy 310-322
   4. Interpretation of Vibrational Spectra 322-331
3. Thermal Analysis 333-365 (Not scope of the course)

**Nanoindentation paper (part of exam material)**

**“Nanoindentation Examination of Crystalline Solid Surfaces”**

1. General Introduction

2. General Remarks on Existing Models and Conventional Analyses of Depth-Sensing

Indentation Data

3. Atomistic Simulation of the Nanoindentation Process

4. Nanoindentation of Ceramics, Semiconductors, and Superconductors

5. Summarizing Remarks

Conventions and Notations